

**Notice of References Cited**

Application/Control No.

09/776,329

Applicant(s)/Patent Under  
Reexamination  
SEUTTER ET AL.

Examiner

Toniae M. Thomas

Art Unit

2822

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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